Application/Control No. O9/911,155 Applicant(s)/Patent Under Reexamination PARIKH ET AL. Examiner Shouxiang Hu Applicant(s)/Patent Under Reexamination PARIKH ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	ď					
	R					
	S	•		_		
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	υ	American Institute of Physics Handbook, pages 9-172–9-177, 1982		
	٧	Denisenko et al., Device Research Conference, Denver, CO, USA, pages 75-76, June 2000.		
	w			
	х			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.